

CE EMC TEST REPORT

Report No.: DDT-B23090108-2E01

Applicant	:	TPV Electronics (Fujian) Co., Ltd.
Address	:	Rongqiao Economic and Technological Development Zone, Fuqing City, Fujian Province, P.R. China
Equipment under Test	:	LCD Monitor
Model No.	:	**27G4***** ("*" = 0-9, A-Z, a-z, +, -, /, \ or blank)
Trade Mark	:	AOC

Issued By: Tianjin Dongdian Testing Service Co., Ltd.

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Test Report Declare

Applicant	: TPV Electronics (Fujian) Co., Ltd.
Address	: Rongqiao Economic and Technological Development Zone, Fuqing City, Fujian Province, P.R. China
Equipment under Test	: LCD Monitor
Model No.	: **27G4***** ("*" = 0-9, A-Z, a-z, +, -, /, \ or blank)
Trade Mark	: AOC

Test Standard Used:

AS/NZS CISPR 32:2015 AMD 1:2020,BS EN 55032:2015,BS EN 55032:2015+A11:2020,
BS EN 55032:2015+A1:2020,BS EN 55035:2017,BS EN 55035:2017+A11:2020,
BS EN 61000-3-2:2014,BS EN 61000-3-3:2013,BS EN 61000-3-3:2013+A1:2019,
BS EN 61000-3-3:2013+A2:2021,BS EN IEC 61000-3-2:2019+A1:2021,
CISPR 32:2015/AMD1:2019,CISPR 35:2016,EN 55032:2015,EN 55032:2015/A11:2020,
EN 55032:2015/A1:2020,EN 55035:2017,EN 55035:2017/A11:2020,EN 61000-3-2:2014,
EN 61000-3-3:2013,EN 61000-3-3:2013/A1:2019,EN 61000-3-3:2013/A2:2021,
EN IEC 61000-3-2:2019/A1:2021,IEC 61000-4-11:2020,IEC 61000-4-2:2008,
IEC 61000-4-3:2020,IEC 61000-4-4:2012,IEC 61000-4-5:2014/AMD1:2017,
IEC 61000-4-6:2013,IEC 61000-4-8:2009

We Declare:

The equipment described above is tested and assessed by Tianjin Dongdian Testing Service Co., Ltd. and in the configuration assessed the equipment complied with the standards specified above. The tested and assessed results are contained in this test report and Tianjin Dongdian Testing Service Co., Ltd. is assumed of full responsibility for the accuracy and completeness of these assessments.

After test and evaluation, our opinion is that the equipment provided for test compliance with the requirement of the above standards.

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Revision History

Rev.	Revisions	Issue Date	Revised By
---	Initial issue	Sep. 13, 2023	